

IN THE CLAIMS:

Please amend claims 1, 10 and 11 as follows.

1. (Currently Amended) A method, comprising:

determining if a memory section is functional based on memory BIST data;

selecting a redundant memory section if the memory section is determined to be nonfunctional;

determining if at least the selected redundant memory is functional according to a BIST;

selecting a further redundant memory section if the selected redundant memory section is determined to be non-functional;

repeating selection of the further redundant memory section ~~an alternate redundant memory section~~, if the selected further redundant memory section ~~or if the selected alternate redundant memory section~~ is non-functional, until ~~at least one of the selected further redundant memory section or the selected alternate redundant memory section~~ is determined to be functional or all redundant memory sections have been selected; and

updating a redundant memory data structure to indicate that ~~at least one of the selected redundant memory section or the selected alternate redundant memory section~~ is no longer redundant.

2. (Original) The method of claim 1, further comprising storing data indicating the selected redundant memory section.

3. (Original) The method of claim 1, further comprising outputting a pass or fail signal based on the determining if at least the selected redundant memory is functional according to a BIST.

4. (Original) The method of claim 1, wherein the redundant memory section includes a column or row.

5. (Original) The method of claim 1, wherein the redundant memory section includes a bit.

6. (Original) The method of claim 1, wherein the selecting selects a redundant memory section from a redundant memory data structure.

7. (Cancelled)

8. (Original) The method of claim 1, wherein the method is performed during a manufacturing process.

9. (Original) The method of claim 1, wherein the method is performed during power up of an integrated circuit.

10. (Currently Amended) A system, comprising:

means for determining if a memory section is functional based on memory BIST data;

means for selecting a redundant memory section if the memory section is determined to be nonfunctional;

means for determining if at least the selected redundant memory is functional according to a BIST;

means for selecting a further redundant memory section if the selected redundant memory section is determined to be non-functional;

means for repeating selection of the further redundant memory section ~~an alternate redundant memory section~~, if the selected further redundant memory section ~~or if the selected alternate redundant memory section~~ is non-functional, until at least one of the selected further redundant memory section ~~or the selected alternate redundant memory section~~ is determined to be functional or all redundant memory sections have been selected; and

means for updating a redundant memory data structure to indicate that ~~at least one of the selected redundant memory section or the selected alternate redundant memory section~~ is no longer redundant.

11. (Currently Amended) A system, comprising:

a BIST capable of determining if a memory section is functional; and
self-adaptive logic, communicatively coupled to the BIST, capable of selecting a
redundant memory section if the memory section is determined to be nonfunctional;
wherein the BIST is further capable of determining if at least the selected
redundant memory is functional, selecting a further redundant memory section if the
selected redundant memory section is determined to be non-functional, repeating
selection of ~~an alternate~~ the further redundant memory section, if the selected further
redundant memory section ~~or if the alternate redundant memory section is non-functional~~,
until ~~at least one of the selected~~ further redundant memory section ~~or the alternate
redundant memory section is determined to be functional or all redundant memory~~
sections have been selected, and updating a redundant memory data structure to indicate
that the selected redundant memory section ~~or the alternate redundant memory section is~~
no longer redundant.

12. (Original) The system of claim 11, further comprising a register
communicatively coupled to the self-adaptive logic and wherein the self-adaptive logic is
further capable of storing data indicating the selected redundant memory section in the
register.

13. (Original) The system of claim 11, further comprising a pin and wherein the self-adaptive logic is further capable of outputting a pass or fail signal based on the BIST determination of the functionality of the selected redundant memory.

14. (Original) The system of claim 11, wherein the redundant memory section includes a column or row.

15. (Original) The system of claim 11, wherein the redundant memory section includes a bit.

16. (Original) The system of claim 11, further comprising a redundant memory data structure listing redundant memory sections and wherein the self-adaptive logic selects a redundant memory section from the redundant memory data structure.

17. (Cancelled)

18. (Original) The system of claim 11, wherein the BIST and the self-adaptive logic function during a manufacturing process.

19. (Original) The system of claim 11, wherein the BIST and the self-adaptive logic function during power up of the system.